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3.5 A $\pm 25A$ Versatile Shunt-Based Current Sensor with 10kHz Bandwidth and $\pm 0.25\%$ Gain Error from -40° C to 85°C Using 2-Current Calibration

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Accurate current sensing is critical in many industrial applications, such as battery management and motor control. Precise shunt-based current sensors have been reported with gain errors of less than 1% over the industrial temperature range (-40°C to 85°C) [1-4]. However, since they are intended for coulomb counting, their bandwidth is limited to a few tens of Hz, making them unsuitable for battery impedance or motor-current sensing. This paper presents a current sensor with a wide (10kHz) bandwidth and a tunable temperature compensation scheme (TCS), which allows it to be flexibly used with different types of shunts while maintaining high accuracy. A low-cost room-temperature calibration scheme is proposed to optimize gain flatness over temperature by exploiting the shunt's self-heating at large currents. Over the industrial temperature range and a ±25A current range, it achieves state-of-the-art gain error (±0.25%) with both low-cost PCB and stable metal-alloy shunts.

A block diagram of the proposed current sensor is shown in Fig. 3.5.1. It digitizes the voltage V_S across a shunt connected between the load and ground. The shunt may be realized as a low-cost PCB trace, whose large temperature coefficient (TC, ~0.4%/K) must then be compensated to mitigate errors due to ambient temperature drift and self-sheating. Higher accuracy can be achieved by using low-TC metal-alloy shunts, but this comes at the expense of cost. To be compatible with both types of shunts, the proposed sensor employs an ADC with a reference voltage V_{REF} whose TC can be tuned to match that of the shunt. As a result, the output of the ADC D_{OUT} is temperature-independent and does not require further processing [3]. V_{REF} is generated by combining a PTAT voltage V_{PTAT} with an attenuated CTAT voltage $V_{CTAT}/\alpha \pm V_{CTAT}/\lambda$, where λ (>80) is used for fine-tuning and α (=10) provides the attenuation needed to realize the reverse-bandgap voltage required by a low TC shunt. As in [3], an NPN-based reference generator is used to generate V_{PTAT} (ΔV_{BE}) and V_{CTAT}/V_{BE}).

Figure 3.5.2 shows a single-ended block diagram of the proposed readout circuit. Since V_S voltage is small ($|V_S| < 50 \text{mV}$), it is boosted by a capacitively-coupled amplifier (CCA), which also serves as the summing node of a 1-bit 2^{nd} -order switched-capacitor (SC) $\Delta\Sigma$ modulator. The CCA's gain ($10\times$) suppresses the offset and kT/C noise of the modulator's 1^{nd} integrator, allowing the use of small sampling capacitors. To efficiently implement the large attenuation λ , the 1-bit feedback $\pm V_{REF}$ is applied via two feedback paths. Its PTAT component (ΔV_{BE}) is applied via the CCA, while its CTAT components (V_{BE}/α and V_{BE}/λ) are applied via the 1^{nd} integrator. Thus, both attenuations are realized by reasonable capacitor ratios: λ (= $C_{IIV}/C_{FB}\times C_1/C_2$) and α (= $C_{IIV}/C_{FB}\times C_1/C_3$), where C_{IN} = $10C_{FB}$ = 500FF. C_1 = C_3 = $8C_2$ = 400FF. Since the capacitors are rather small, λ is trimmed in a $\Delta\Sigma$ fashion, rather than by using a multi-element DAC [2]. To avoid quantization noise folding, λ is implemented by two separate 1^{st} -order $\Delta\Sigma$ modulators clocked in a bitstream-controlled (BSC) manner [6]. In this way, the CTAT component V_{BE}/λ can be trimmed with 8-bit resolution over a $\pm 9\text{mV}$ range, corresponding to TC steps of ~1.6 and $10\text{ppm}/^{\circ}\text{C}$ for the low-TC and PCB shunts, respectively.

To mitigate its offset and 1/f noise, the CCA is chopped at f_s (=2.56MHz), while the 1st integrator employs a correlated-double-sampling (CDS) scheme. Switched resistors are used to realize the large DC feedback resistances (>100M Ω) needed to ensure that the CCA's highpass cut-off frequency is well below f_s . The CDS scheme also demodulates the CCA's output, thus rejecting its offset without the need for the ripple-reduction loop used in [5]. Residual offset is suppressed by system-level chopping (CHL, f_{CHL} =20kHz). However, the resulting transients will disturb the state of the modulator, causing significant errors. In this work, rather than resetting the modulator during each CHL transition [1-3], the position of the integration capacitors is periodically swapped, thus preserving modulator state and enabling free-running operation [6]. To compensate for the loop filter's delay, the clock of the output chopper is delayed by one $\Delta\Sigma$ clock period.

The CCA is based on a 2-stage Miller-compensated amplifier, which consists of a folded-cascode input stage and a Class-AB output stage. Drawing ~180μA, it provides >100dB DC gain and rail-to-rail output swing. The SC integrators are based on current-reuse OTAs. For diagnostic purposes, an on-chip temperature sensor is implemented to monitor the self-heating of the shunt at large currents. This consists of a separate 1st-order SC ΔΣ modulator that balances 11•ΔV_{BE} against V_{BE} to generate a digital representation of temperature [6].

The sensor was implemented in a standard 0.18µm CMOS technology. Including the reference generator and current-sensing ADC, it occupies 0.36mm² (Fig. 3.5.7, right) and draws 265µA from a 1.8V supply. For flexibility, the sinc² decimation filter and BSC $\Delta\Sigma$ trimming logic are implemented off-chip. The sensor's performance was verified with $1.6m\Omega$ PCB (36mm×5mm), and 2m Ω low-TC (75ppm/°C) shunts (Fig. 3.5.7, left). Good thermal coupling and galvanic isolation were achieved by directly bonding the chip to the shunt with non-conductive glue.

Figure 3.5.3 (top) shows the measured output spectra of the modulator. Trimming V_{REF} with a free-running digital $\Delta\Sigma$ modulator incurs significant noise folding, which is eliminated by the BSC scheme. The modulator then achieves a thermal-noise-limited resolution of $8.5\mu Vrms$ in a 10kHz bandwidth. With CHL disabled, measurements on 20 samples show that the sensor's offset is less than 50 μV . This drops below $6\mu V$ with CHL enabled. Figure 3.5.3 (bottom) shows the D_{OUT} variations of the sensor measured from -40°C to 85°C with a 15A input. The BSC $\Delta\Sigma$ trimming scheme allows D_{OUT} variation to be trimmed with high resolution, in steps of ~0.1% and ~0.03% for the PCB and low-TC shunts, respectively. With an optimal λ , D_{OUT} variations can be reduced to less than ±0.1% over the industrial temperature range for both shunts.

With a PCB shunt and a 0-to-5A step, the sensor's output settles to within 0.2% in 300µs (Fig. 3.5.4, left). However, a 0-to-25A step causes significant self-heating and slow settling; a temperature rise of ~10°C was observed over a 14s interval. Due to the initially non-homogenous temperature distribution in the shunt, a peak settling error of 0.7% can be seen, which drops to 0.2% within ~6s (Fig. 3.5.4, right).

By exploiting the shunt's self-heating at large currents, the optimal λ for minimum D_{OUT} variation over temperature can then be determined by a low-cost 2-current calibration at room temperature. For example, currents of 10A and 25A will result in a significant temperature difference, ~20°C for the PCB shunt, resulting in a significant error in the expected gain of 2.5 before λ optimization. Due to the residual high-order TC of both the shunt and V_{REF} , the optimal λ then corresponds to a non-zero gain error, which is obtained by batch calibration. After determining the optimal λ , the 10A current is then used to trim the gain error due to the spread of the shunt's nominal resistance. Ten sensors were characterized for each type of shunt in a current range of ±25A from -40°C to 85°C. With an optimized, but fixed, value of λ (~177 (PCB shunt) and ~683 (low-TC shunt)) and a single-current-gain trim [2], gain errors of ±0.4% (PCB shunt) and ±0.3% (low-TC shunt) were achieved. The proposed 2-current calibration scheme reduces them to ±0.25% (PCB shunt) and ±0.2% (low-TC shunt) without further processing (Fig. 3.5.5). The spread on the resulting values of λ , which reflects the combined spread in the TC of the shunt and V_{REF} , is limited to 10 and 20 LSBs for the PCB and low-TC shunts, respectively.

The performance of the sensor is summarized in Fig. 3.5.6 and compared with state-of-the-art PCB and low-TC shunt-based sensors. The proposed sensor achieves the highest bandwidth with competitive power efficiency. For both types of shunts, thanks to the low-cost 2-current calibration scheme, it achieves state-of-the-art gain accuracy (±0.25%) over a wide current (±25A) and temperature (-40°C to 85°C) range.

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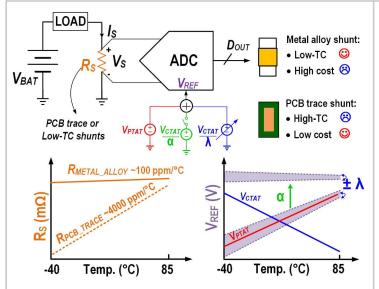
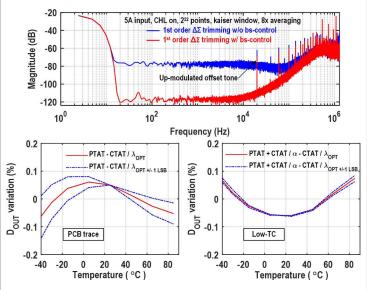


Figure 3.5.1: Block diagram of the proposed current sensor with Low-TC and PCB Figure 3.5.2: Simplified single-ended circuit diagram of the fully-differential current trace shunts.



D_{OUT} variations over temperature with a 15A current input (bottom).

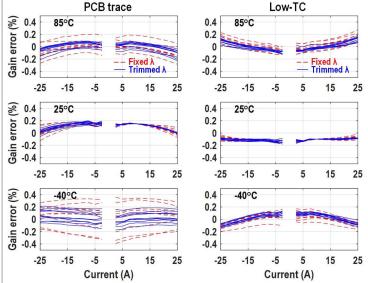
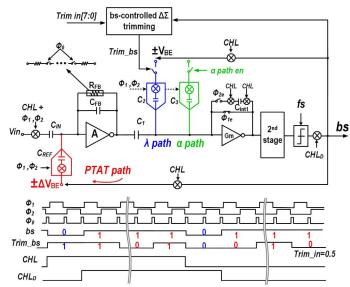


Figure 3.5.5: Measured gain errors at different ambient temperatures for PCB trace (left) and low-TC metal alloy shunt (right) w/ and w/o λ trimming.



sensor and its timing diagram.

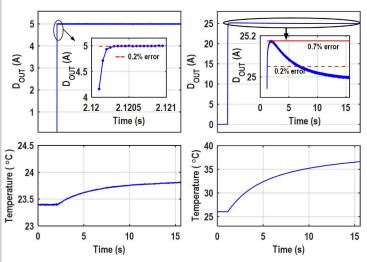


Figure 3.5.3: Measured output spectra w/ and w/o BSC ΔΣ trimming (top); measured Figure 3.5.4: Transient measurements under 0 to 5A (left) and 0 to 25A (right, 16× averaging) current-step inputs with a PCB trace shunt.

	This work		Xu SSCL' 18 [1]	Zamparette VLSI' 21 [2]	Vroonhoven ISSCC' 20 [4]	INA 260
Tech. (µm)	0.18		0.18 BCD	0.18	0.18 BCD	1
Area (mm²)	0.36		1.4	1	0.85	1
Shunt	1.6mΩ (PCB)	2mΩ (low-TC)	1mΩ (PCB)	3mΩ (PCB)	50mΩ (low-TC)	2mΩ (low-TC)
I Range	±25A	±25A	±12A	±15A	±1A	±15 A
Gain Error	±0.25%	±0.2%	±0.35%	±0.6%	±0.5%	±0.5%
Temp. Range	-40 to 85°C		-40 to 85°C	-40 to 85°C	-50 to 125°C	-40 to 85°C
ADC Offset	6µV		1µV	0.5µV	<5µV	10µV
Bandwidth	10kHz		40Hz	32Hz	<2.4Hz	<3.6kHz
ADC Resolution	8.5µV		1.1µV	5.4µV	1	1
Supply Voltage	1.8V		1.8V	1.8V	1.7-60V	2.7-5.5V
Supply Current	265µA		13.8µA	1.4µA	<5µA	310µA
Dynamic Range	73.5dB	75.4dB	80.7dB	78.4 dB	1	1
FoM*	147dB	149dB	143dB	149dB	1	1
Polynomial Calibration	No		Yes	Yes	No	1

^{*} FoM=Dynamic Range +10log (Bandwidth/Power)

Figure 3.5.6: Performance summary and comparison table.

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